



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20250618004.1

**Qualification of DFAB as an additional Fab site option for select JI devices
Change Notification / Sample Request**

Date: June 18, 2025

To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) [process](#).

TI requires acknowledgement of receipt of this notification within 60 days of the date of this notice. Lack of acknowledgement of this notice within 60 days constitutes acceptance and approval of this change. If samples or additional data are required, requests must be received within 60 days of this notification, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 60 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

Changes outlined in this notification underscore our commitment to product longevity and supply continuity, as well as our continued efforts to transition to newer, more efficient manufacturing processes and technologies. Specifically, this particular notification is related to TI's multiyear transition plan for our two remaining 150-millimeter production lines (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). SFAB closure activities are expected to begin by the end of 2025. DFAB will remain open with a smaller set of 200mm technologies and GaN.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the Change Management team. For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

TI values customer engagement and feedback related to TI changes. Customers should contact TI if there are questions or concerns regarding a change notification.

Change Management Team
SC Business Services

20250618004.1
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, you have recently purchased these devices. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
SN751701PSR	NULL
SN75155DR	NULL
TPD2E007DCKR	TPD2E007DCKR

Technical details of this Product Change follow on the next page(s).

PCN Number:	20250618004.1		PCN Date:	June 18, 2025																									
Title:	Qualification of DFAB as an additional Fab site option for select JI devices																												
Customer Contact:	Change Management Team		Dept:	Quality Services																									
Proposed 1st Ship Date:	September 16, 2025		Sample requests accepted until:	August 17, 2025*																									
*Sample requests received after August 17, 2025 will not be supported.																													
Change Type:																													
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Material																								
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Process																								
<input type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input checked="" type="checkbox"/>	Wafer Fab Site																								
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input checked="" type="checkbox"/>	Wafer Fab Material																								
<input checked="" type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input checked="" type="checkbox"/>	Wafer Fab Process																								
PCN Details																													
Description of Change:																													
Texas Instruments is pleased to announce the addition of DFAB as an additional Wafer Fab option for the devices listed below.																													
<table border="1"> <thead> <tr> <th colspan="4">Current Fab Site</th> <th colspan="4">Additional Fab Site</th> </tr> <tr> <th>Fab Site</th> <th>Process</th> <th>Metallization</th> <th>Wafer Diameter</th> <th>Fab Site</th> <th>Process</th> <th>Metallization</th> <th>Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td>SFAB</td> <td>JI</td> <td>2300A TiW/ 7.6kA AICu 2%</td> <td>150 mm</td> <td>DFAB</td> <td>JI</td> <td>2300A TiW/ 7.6kA AICu 0.5%</td> <td>200 mm</td> </tr> </tbody> </table>				Current Fab Site				Additional Fab Site				Fab Site	Process	Metallization	Wafer Diameter	Fab Site	Process	Metallization	Wafer Diameter	SFAB	JI	2300A TiW/ 7.6kA AICu 2%	150 mm	DFAB	JI	2300A TiW/ 7.6kA AICu 0.5%	200 mm		
Current Fab Site				Additional Fab Site																									
Fab Site	Process	Metallization	Wafer Diameter	Fab Site	Process	Metallization	Wafer Diameter																						
SFAB	JI	2300A TiW/ 7.6kA AICu 2%	150 mm	DFAB	JI	2300A TiW/ 7.6kA AICu 0.5%	200 mm																						
Qual details are provided in the Qual Data Section.																													
Reason for Change:																													
These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.																													
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																													
None																													
Changes to product identification resulting from this PCN:																													
Fab Site Information:																													
<table border="1"> <thead> <tr> <th>Chip Site</th> <th>Chip Site Origin Code (20L)</th> <th>Chip Site Country Code (21L)</th> <th>Chip Site City</th> </tr> </thead> <tbody> <tr> <td>SH-BIP-1</td> <td>SHE</td> <td>USA</td> <td>Sherman</td> </tr> <tr> <td>DL-LIN</td> <td>DLN</td> <td>USA</td> <td>Dallas</td> </tr> </tbody> </table>		Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City	SH-BIP-1	SHE	USA	Sherman	DL-LIN	DLN	USA	Dallas																
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SH-BIP-1	SHE	USA	Sherman																										
DL-LIN	DLN	USA	Dallas																										
Sample product shipping label (not actual product label):																													
Product Affected:																													

SN75155DR	SN75155DRE4	SN751701PSR.A	TPD2E007DCKR.A
SN75155DR.A	SN751701PSR	TPD2E007DCKR	TPD2E007DCKR.B

For alternate parts with similar or improved performance, please visit the product page on [TI.com](http://ti.com)

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: TPS79801QDGNRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	3/231/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	3/2400/0
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	1/15/0
PD	C4	Physical Dimensions	Cpk>1.67	-	3/30/0
ESD	E2	ESD CDM	-	1000 Volts	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	3/90/0

- QBS: Qual By Similarity, also known as Generic Data
- Qual Device TPS79801QDGNRQ1 is qualified at MSL2 260C
- Qual Device TPS79801QDGNRQ1 is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2203-030

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: SN74LS07DR	QBS Process Reference: LT1013DIDR	QBS Package Reference: ULQ2003AQDRQ1
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0
uHAST	Unbiased HAST, 130C/85%RH	96 Hours	1/77/0	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	1/77/0	3/231/0	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/231/0	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	3/135/0
HTOL	Life Test, 150C	300 Hours	-	3/231/0	3/231/0
ELFR	Early Life Failure Rate, 150C	24 Hours	-	3/2400/0	-
HBM	ESD - HBM	2000 V	1/3/0	-	-
HBM	ESD - HBM	1000 V	1/3/0	1/3/0	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-
LU	Latch-up	(per JESD78)	1/3/0	1/3/0	-
ED	Electrical Distributions	Cpk>1.67 Room, Hot, & Cold Test	1/30/0	3/90/0	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	-

- Qual Devices qualified at LEVEL1-260CG: SN74LS07DR

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2202-009

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: <u>LT1013DIDR</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	3/231/0
HTOL	B1	Life Test	150C	300 Hours	3/231/0
ELFR	B2	Early Life Failure Rate	150C	24 Hours	3/2400/0
ESD	E2	ESD CDM	-	500 Volts	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0

- QBS: Qual By Similarity

- Qual Device LT1013DIDR is qualified at MSL1 260C

- Qual Device LT1013DIDR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2202-003

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN75C185DWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	2/154/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	3/231/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	1/22/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0

- QBS: Qual By Similarity
- Qual Device SN75C185DWR is qualified at MSL1 260C
- Qual Device SN75C185DWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2202-030

In performing change qualifications, Texas Instruments follows integrated circuit industry standards in performing defect mechanism analysis and failure mechanism-based accelerated environmental testing to ensure wafer fab process, assembly process and product quality and reliability. As encouraged by these standards, TI uses both product-specific and generic (family) data in qualifying its changes. For devices to be categorized as a 'product qualification family' for generic data purposes, they must share similar product, wafer fab process and assembly process elements. The applicability of generic data (also known at TI as Qualification by Similarity (QBS)) is determined by the Reliability Engineering function following these industry standards. Generic data is shown in the qualification report in columns titled "QBS Process" (for wafer fab process), "QBS Package" (for assembly process) and "QBS Product" (for product family).

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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